

## Product Description

Super Sharp High Resolution Silicon AFM Cantilevers NSG30\_SS series are designed for Semicontact ( Intermittent ), Noncontact applications. Typical Resonant Frequency 320 kHz (guaranteed range 240-440 kHz), Typical Force Constant 40 N/m (guaranteed range 22-100 N/m). Typical tip curvature radius is 2nm.

Using the probes with sharpened tips you will be able to increase resolution of the obtained images especially on objects with typical sizes of several nanometers.

Cantilever has Al reflective side coating to increase laser signal.

Probes are packed in boxes with 5 pieces.

### General Features

Material	Single Crystal Silicon, N-type, 0.01-0.025 Ohm-cm, Antimony doped
Chip size	3.4x1.6x0.3mm
Reflective side coating	Al
Tip coating	No
Tip curvature radius	typical 2nm, guaranteed 5nm

### Special Features

Cantilever series	Cantilever length, L±10µm	Cantilever width, W±7.5µm	Cantilever thickness, T±1µm	Resonant frequency, kHz			Force constant, N/m		
				min	typical	max	min	typical	max
NSG30_SS	125	30	4.0	240	320	440	22	40	100